

<b>Notice of References Cited</b>	Application/Control No. 10/736,838		Applicant(s)/Patent Under Reexamination SON, HEE-KWAN	
	Examiner DEVIN ALMEIDA		Art Unit 2132	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,646,257	02-1987	Essig et al.	708/630
	B	US-			
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	D	US-			
	E	US-			
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#### NON-PATENT DOCUMENTS

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